

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	Wen-Ying P. Chen	
		2871	Page 1 of 1	

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*	B	US-2002/0044249	04-2002	Hirota, Naoto	349/146
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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